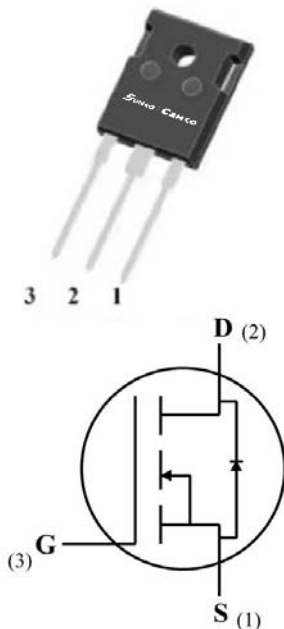


Silicon Carbide Power MOSFET (N-Channel Enhancement)

V_{DS}	1200V
I_D (25°C)	38A
$R_{DS(on)}$	80mΩ



Features

- High speed switching
- Essentially no switching losses
- Reduction of heat sink requirements
- Maximum working temperature at 175 °C
- High blocking voltage
- Fast Intrinsic diode with low recovery current
- High-frequency operation
- Halogen free,

Typical Applications

Typical applications are in power factor correction(PFC), solar inverter, uninterruptible power supply, motor drives, photovoltaic inverter, electric car and charger.

Mechanical Data

- **Package:** TO-247AB
- **Terminals:** Tin plated leads
- **Polarity:** As marked

■Maximum Ratings (T_c=25°C Unless otherwise specified)

PARAMETER	SYMBOL	UNIT	VALUE	TEST CONDITIONS	NOTE
Device marking code			D212080NCTG1		
Drain source voltage @ T _j =25°C	$V_{DS,max}$	V	1200	$V_{GS}=0\text{ V}$, $I_D=100\mu\text{A}$	
Gate source voltage @ T _j =25°C	$V_{GS,max}$	V	-8/+22	Absolute maximum values	Note1
Gate source voltage @ T _j =25°C	$V_{GS,op}$	V	-4/+18	Recommended operational values	Note2
Continuous drain current @ T _c =25°C	I_D	A	38	$V_{GS}=18\text{V}$, T _c =25°C	Fig.18
Continuous drain current @ T _c =100°C			28	$V_{GS}=18\text{V}$, T _c =100°C	
Pulsed drain current	$I_{D(pulsed)}$	A	80	Pulse width t_p limited by T _{j,max}	Fig.23
Power Dissipation	P_{TOT}	W	214	T _c =25°C, T _j = 175°C	Fig.17
Power Dissipation			94	T _c =110°C, T _j = 175°C	
Operating junction and Storage temperature range	T _j , T _{stg}	°C	-55 to +175		
Soldering temperature	T _L	°C	260	1.6mm (0.063") from case for 10s	
Mounting torque	T _M	Nm	0.6	M3 screw Maximum of mounting process: 3	

■Static Electrical Characteristics (Tc=25°C unless otherwise specified)

PARAMTETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Gate threshold voltage	$V_{GS(th)}$	V	2.3	2.9	3.6	$V_{DS}=V_{GS}, I_D=5mA$	Fig.4, 11
				2.2		$V_{DS}=V_{GS}, I_D=5mA, T_J=175^{\circ}C$	
Drain source breakdown voltage	$V_{(BR)DSS}$	V	1200			$V_{GS}=0, I_D=100\mu A$	
Zero gate voltage drain current	I_{DSS}	μA		1	10	$V_{DS}=1200V, V_{GS}=0V$	Fig.16
Gate source leakage current	I_{GSS}	nA			100	$V_{GS}=18V, V_{DS}=0V$	
Current drain source on-state resistance	$R_{DS\ ON}$	m Ω		77	85	$V_{GS}=18V, I_D=20A$	Fig.5, 6, 7
				122		$V_{GS}=18V, I_D=20A, T_J=175^{\circ}C$	
Internal gate resistance	R_g	Ω		1.5		f=1MHz	
Diode forward voltage	V_{SD}	V		3.9		$V_{GS}=-4V, I_{SD}=10A$	Fig.8
				3.2		$V_{GS}=0V, I_{SD}=10A, T_J=175^{\circ}C$	Fig.9
Transconductance	g_r	S		10		$V_{DS}=16V, I_D=20A$	Fig.4
				9.2		$V_{DS}=16V, I_D=20A, T_J=175^{\circ}C$	

■Dynamic Electrical Characteristics (Tc=25°C unless otherwise specified)

PARAMTETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Input capacitance	C_{iss}	pF		890		$V_{DS}=1000V, V_{GS}=0V, T_J=25^{\circ}C, f=1MHz, V_{AC}=25mV$	Fig.13, 14
Output capacitance	C_{oss}			58			
Reverse capacitance	C_{rss}			4			
Coss stored energy	E_{oss}	μJ		34			Fig.15
Gate source charge	Q_{gs}	nC		12		$V_{DS}=800V, V_{GS}=-4/18V, I_D=20A$	Fig.12
Gate drain charge	Q_{gd}			11			
Gate charge	Q_g			41			

■Switching Characteristics (Tc=25°C unless otherwise specified)

PARAMTETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Turn on switching energy	E _{on}	uJ		320		V _{DD} =800V, V _{GS} =-4/+18V, I _D =20A, R _g =0Ω, L=120uH	Fig.21, 22
Turn off switching energy	E _{off}			49			
Turn on delay time	t _{d(on)}	ns		19			
Rise time	t _r			21			
Turn off delay time	t _{d(off)}	ns		15		V _{DD} =800V, V _{GS} =-4/+18V, I _D =20A, R _g =0Ω, L=220uH	Fig.21, 22
Fall time	t _f			17			

■Body diode characteristics (Tc=25°C unless otherwise specified)

PARAMTETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Diode forward voltage	V _{SD}	V		3.9		V _{GS} =-4V, I _{SD} =10A	Fig.8
				3.2		V _{GS} =0V, I _{SD} =10A, T _j =175°C	Fig.9
Continuous diode forward current	I _s	A		38		Tc=25°C	Note1
Reverse recovery time	trr	nS		41		V _R =800V, V _{GS} =-4V, I _D =20A, di/dt=700A/uS	
Reverse recovery charge	Qrr	nC		405			
Peak reverse recovery current	Irrm	A		20			

Note 1: When using SiC Body Diode the maximun recommended V_{GS} = -4V

Note 2: MOSFET can also safely operate at 0/18 V

■Thermal Characteristics (T_a=25°C Unless otherwise specified)

PARAMETER	SYMBOL	UNIT	Value
Thermal resistance	R _{θJ-C}	°C /W	0.7

Typical Characteristics

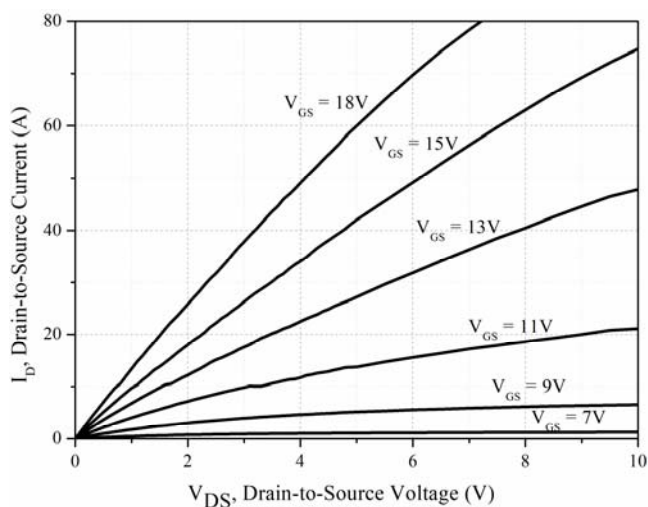


Figure 1. Output Characteristics $T_j = -40^\circ\text{C}$

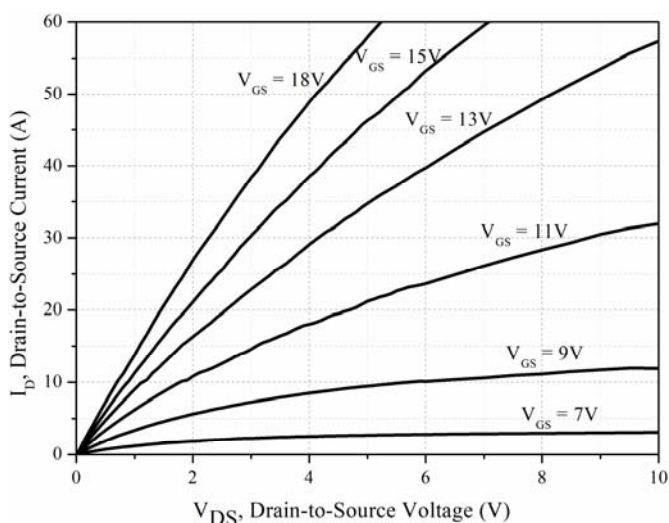


Figure 2. Output Characteristics $T_j = 25^\circ\text{C}$

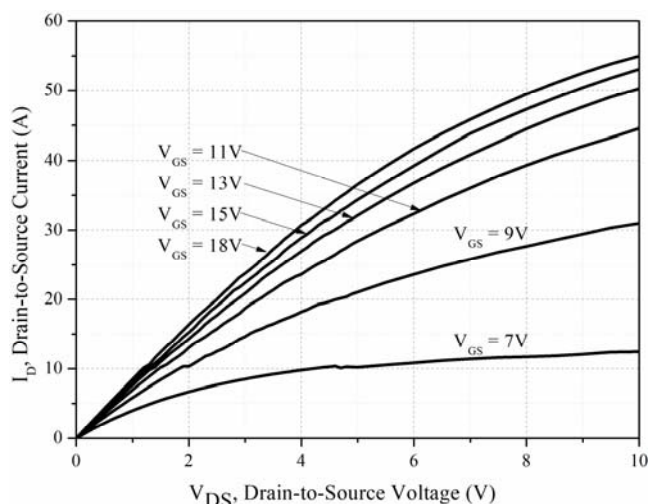


Figure 3. Output Characteristics $T_j = 175^\circ\text{C}$

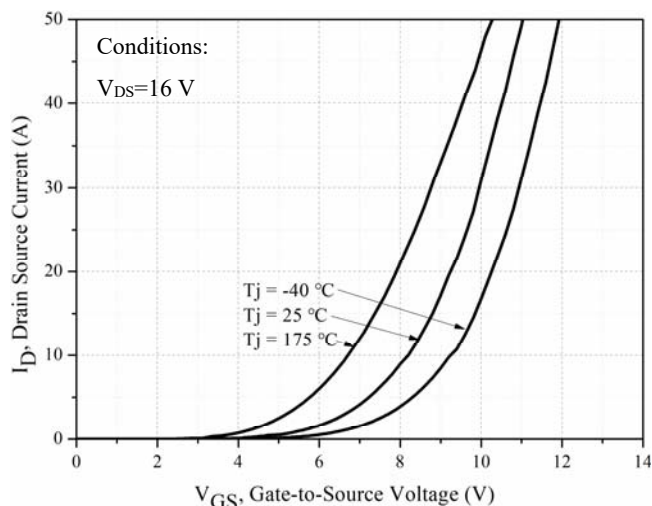


Figure 4. Transfer Characteristics for various junction temperature

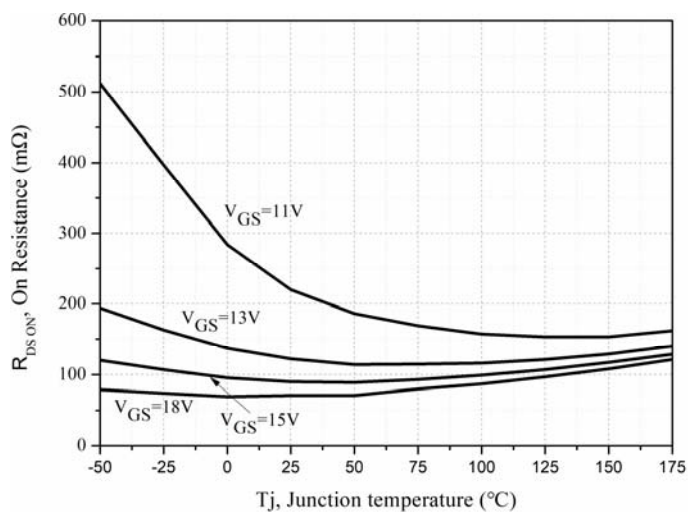


Figure 5. On-resistance vs. temperature for various gate voltage

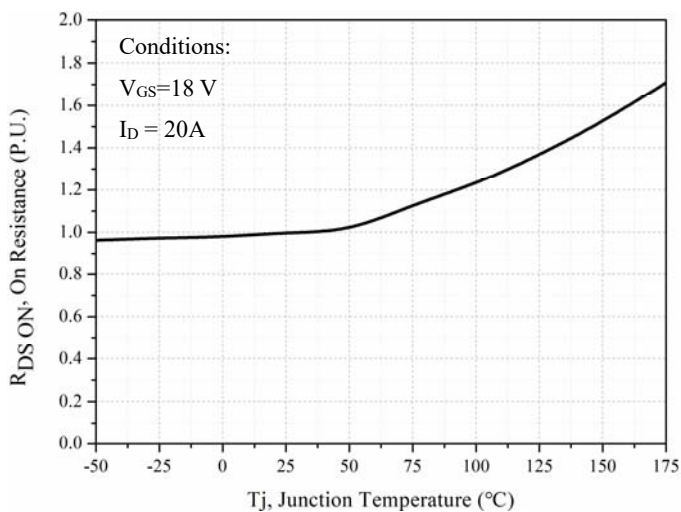


Figure 6. Normalized on-resistance vs. temperature

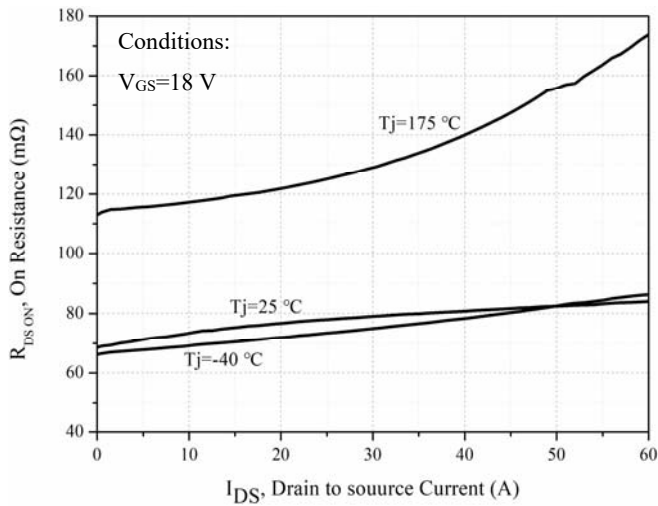


Figure 7. On-resistance vs. drain current

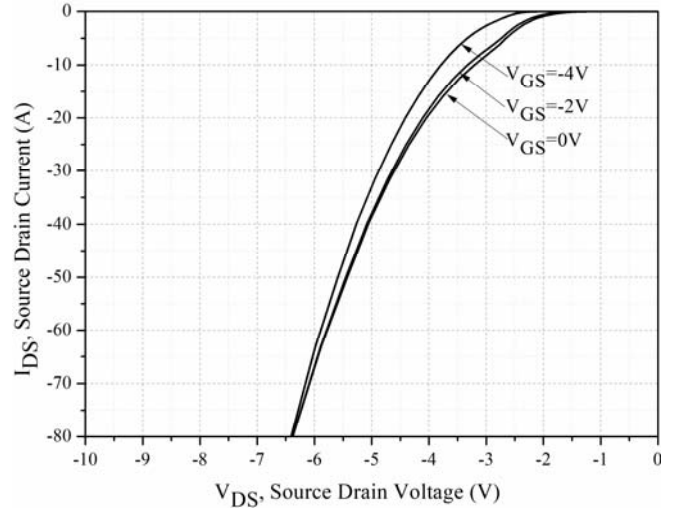


Figure 8. Body diode characteristic at $T_j = 25 \text{ }^{\circ}\text{C}$

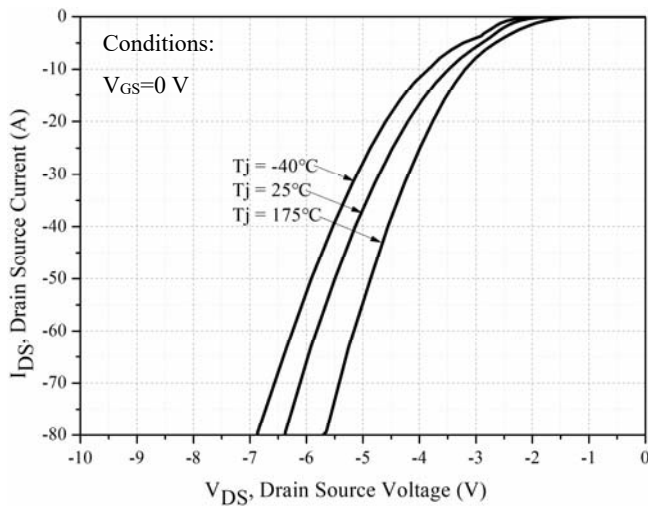


Figure 9. Body diode characteristic

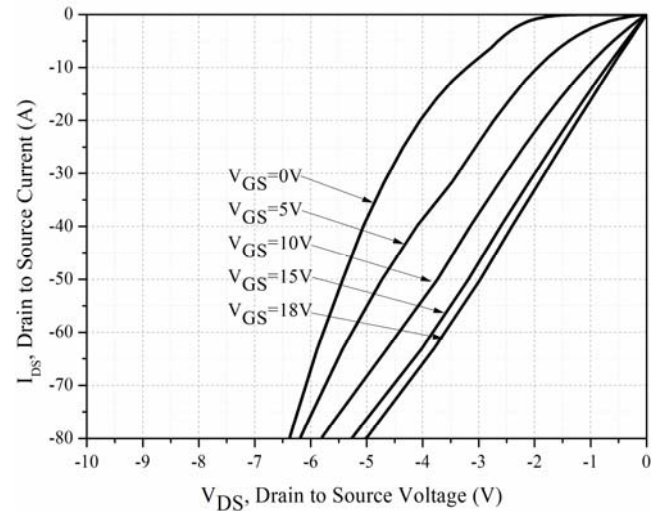


Figure 10. 3rd quadrant characteristic at $T_j = 25 \text{ }^{\circ}\text{C}$

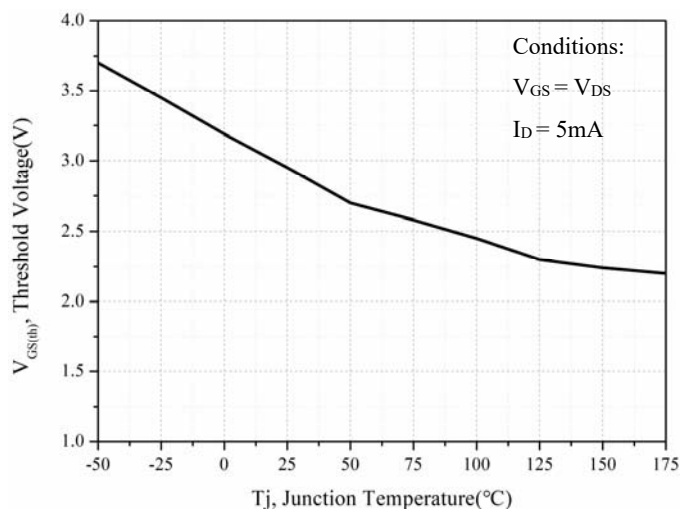


Figure 11. Threshold voltage vs. temperature

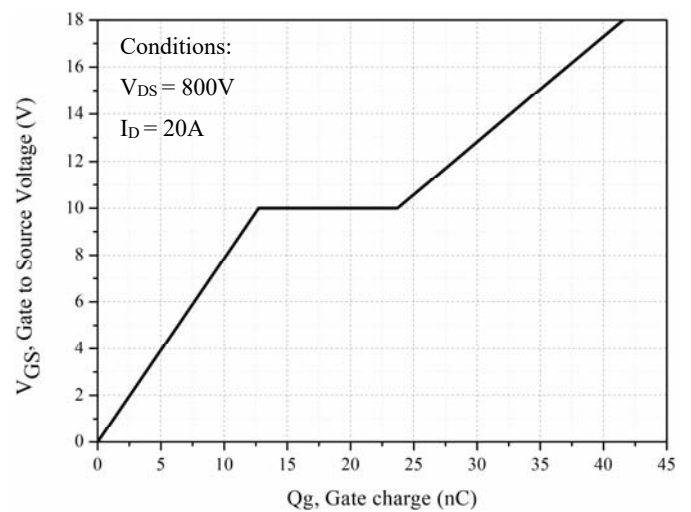


Figure 12. Gate charge characteristic

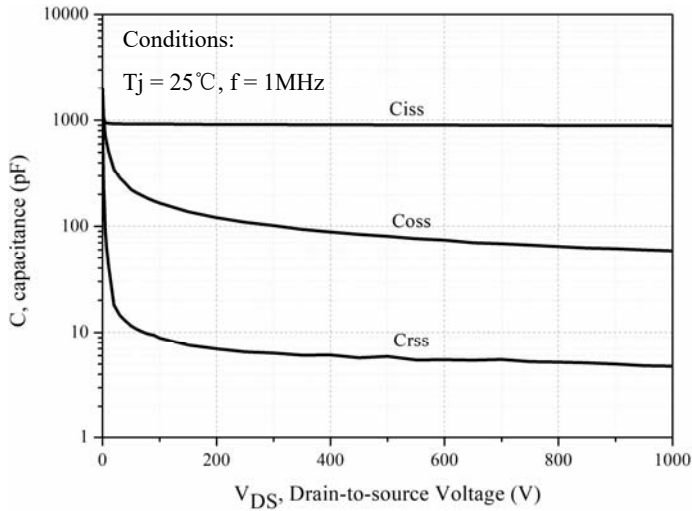


Figure 13. Capacitances vs. drain source voltage (0-1000V)

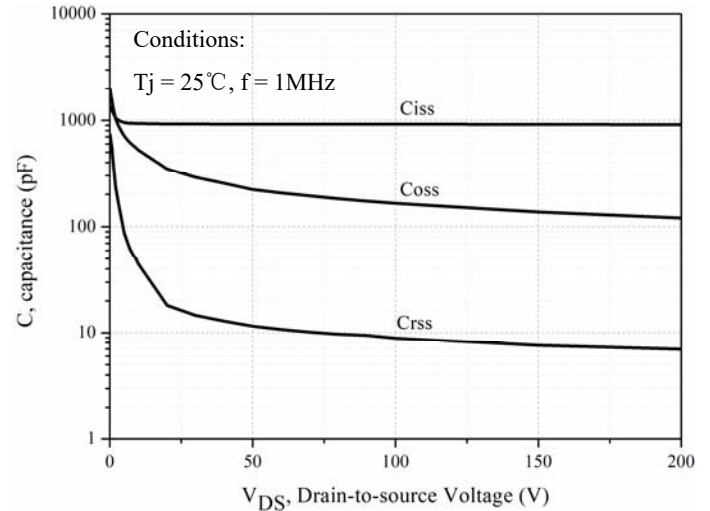


Figure 14. Capacitances vs. drain source voltage (0-200V)

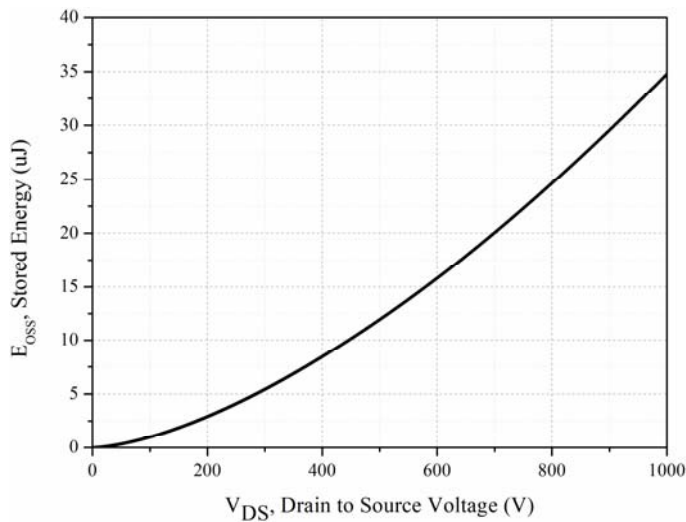


Figure 15. Output capacitor stored energy

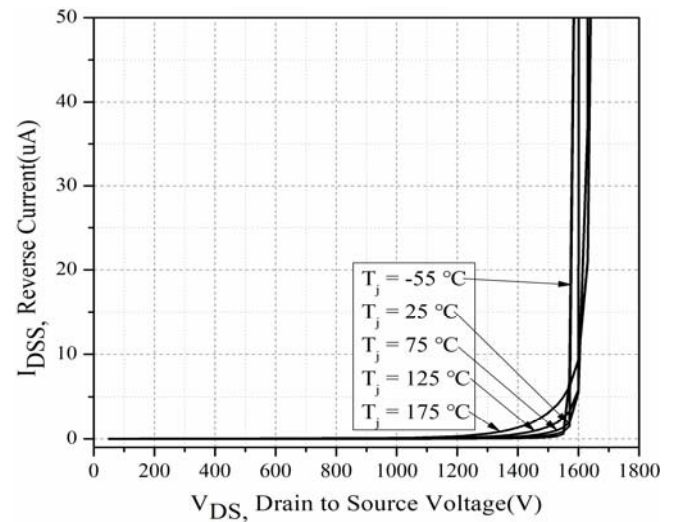


Figure 16. Reverse characteristics vs. Tj

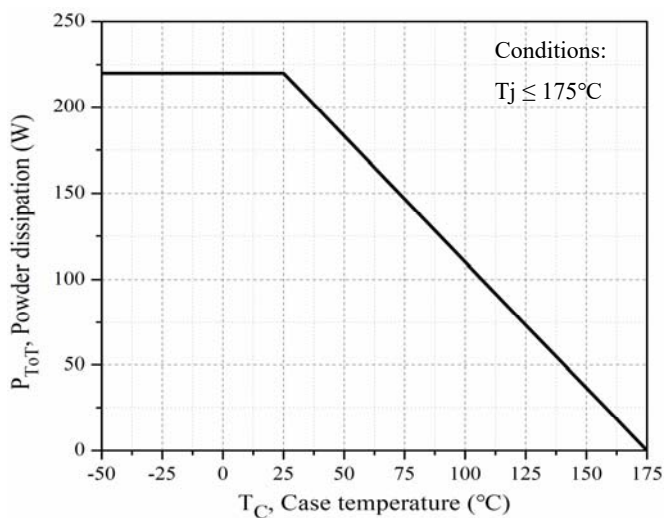


Figure 17. Maximum power dissipation derating vs. case temperature

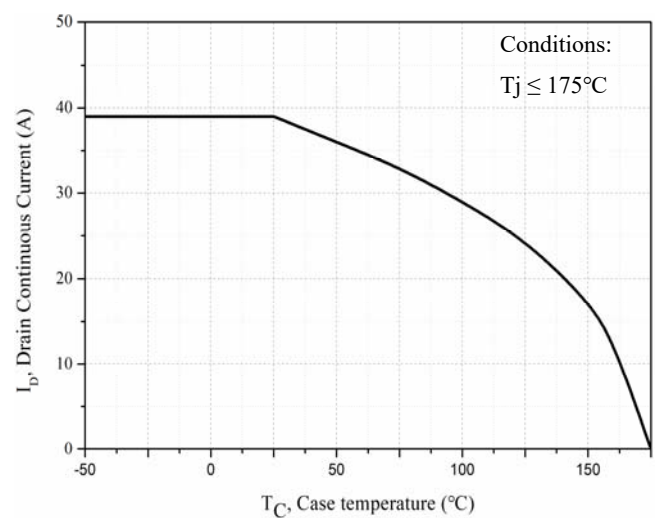


Figure 18. Continuous drain current derating vs. case temperature

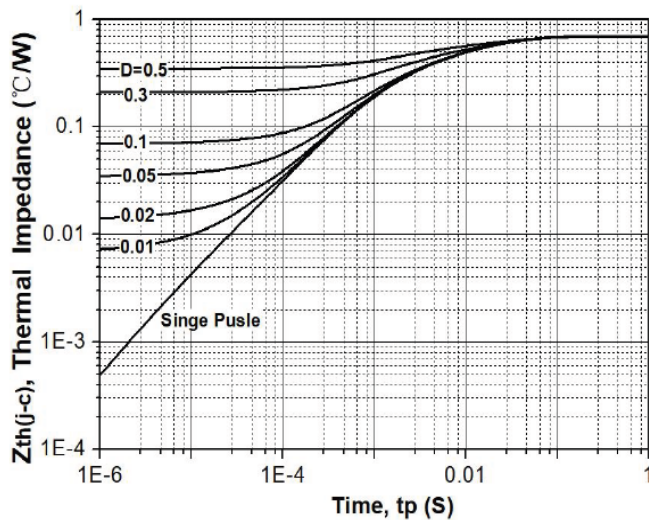


Figure 19. Transient thermal impedance (junction - case)

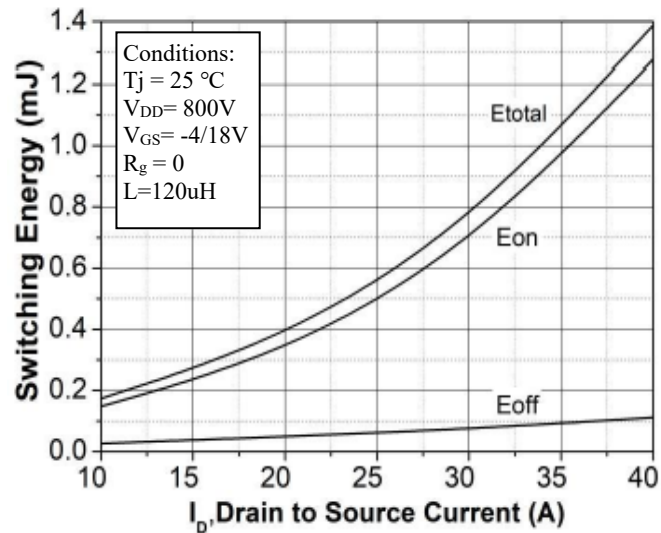


Figure 20. Clamped Inductive switching energy vs. drain current

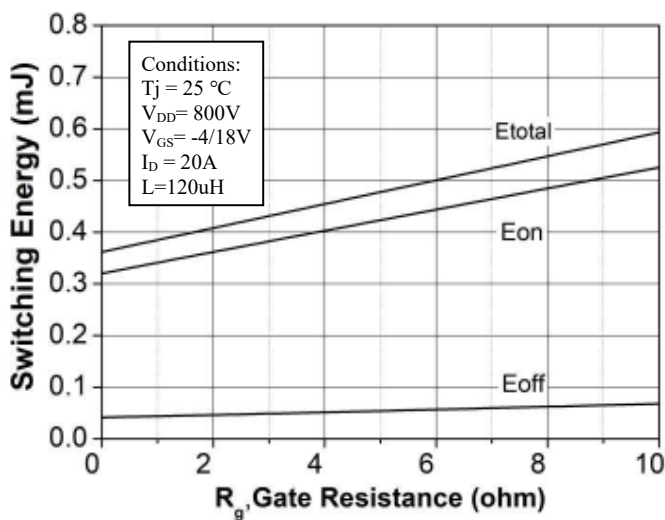


Figure 21. Clamped inductive switching energy vs. Rg

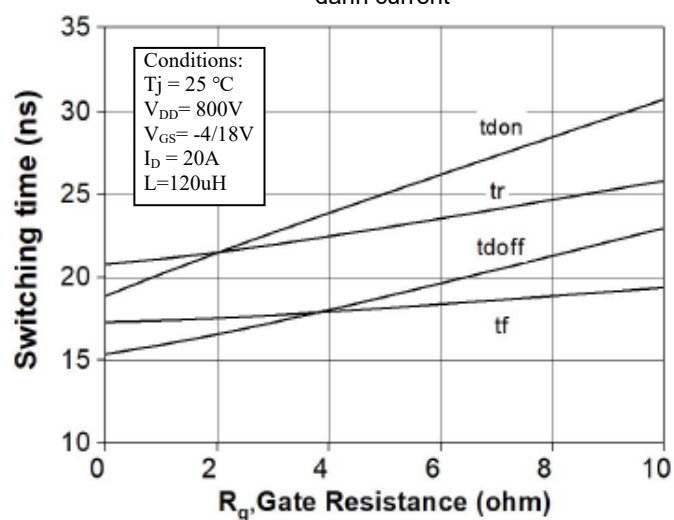


Figure 22. Switching times vs. Rg

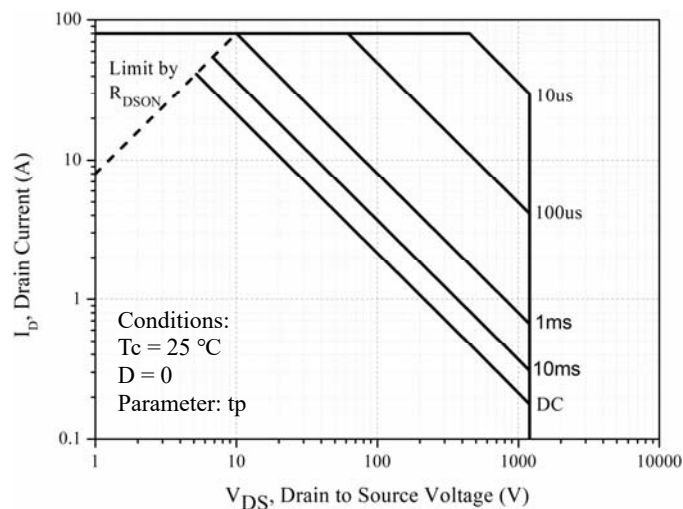


Figure 23. Safe operating area

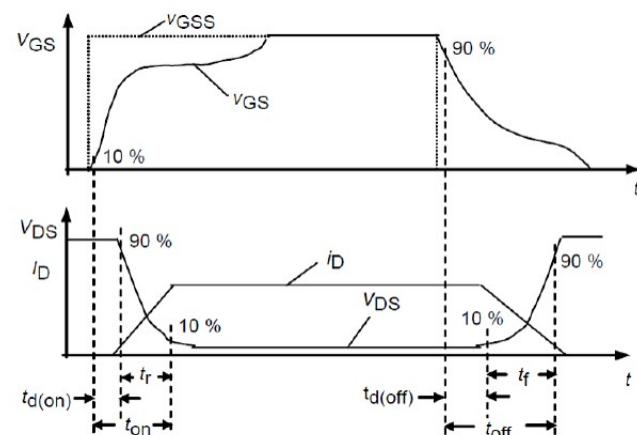


Figure 24. Switching Times Definition

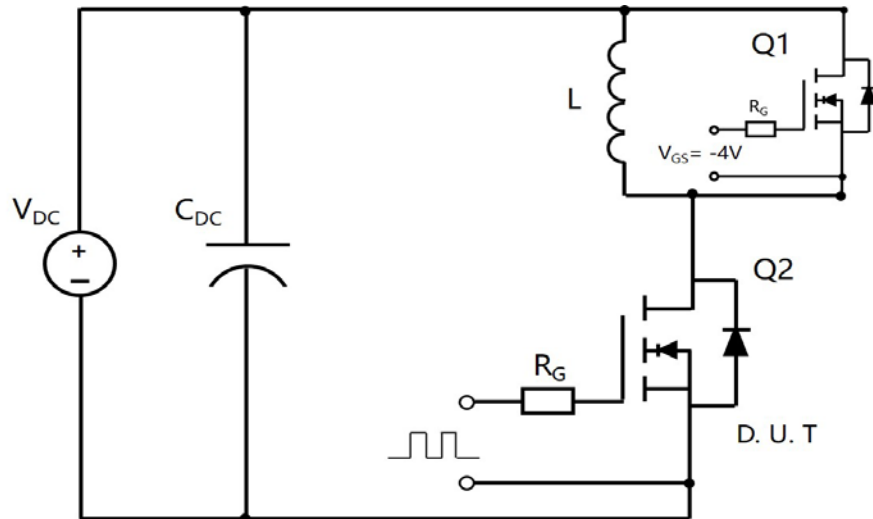
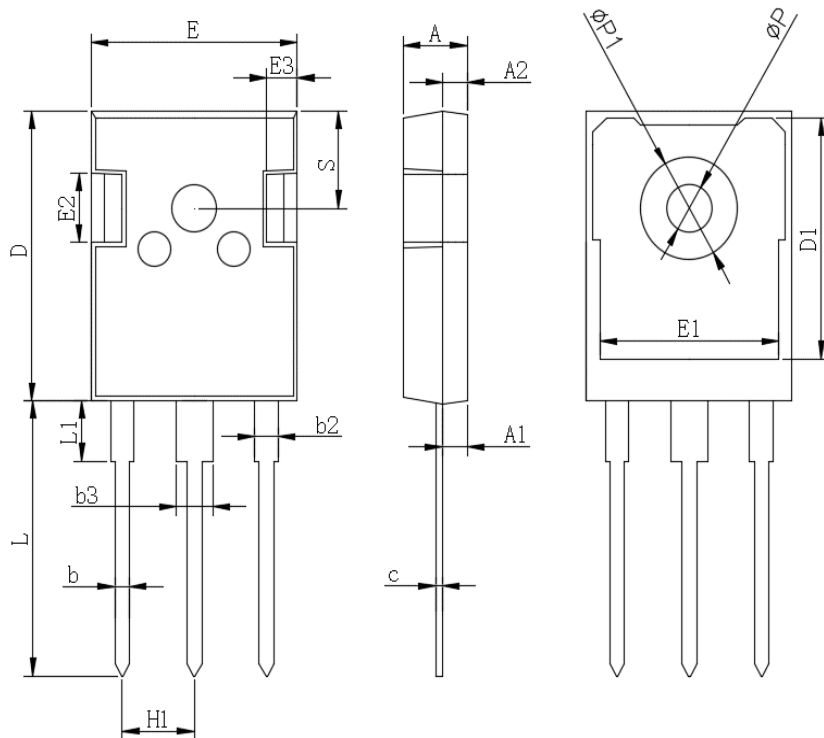


Figure 25. Clamped Inductive Switching Waveform Test Circuit

■Outline Dimensions

TO-247AB



TO-247AB		
Dim	Min	Max
A	4.80	5.20
A1	2.21	2.61
A2	1.85	2.15
b	1.0	1.4
b2	1.91	2.21
C	0.5	0.7
D	20.70	21.30
D1	16.25	16.85
E	15.50	16.10
E1	13.0	13.6
E2	4.80	5.20
E3	2.30	2.70
L	19.62	20.22
L1	-	4.30
ΦP	3.40	3.80
ΦP1	-	7.30
S	6.15TYP	
H1	5.44TYP	
b3	2.80	3.20

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